



Docket No.: 63979-033

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of

Yoshihiko KANZAWA, et al.

Serial No.: 10/674,523

Filed: October 01, 2003

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Confirmation No: 5372

Group Art Unit: Not yet Assigned

Examiner: To be Assigned

For: METHOD FOR MEASURING SEMICONDUCTOR CONSTITUENT ELEMENT  
CONTENT AND METHOD FOR MANUFACTURING A SEMICONDUCTOR DEVICE (As  
amended)

**PRELIMINARY AMENDMENT**

Mail Stop  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Prior to examination of the above-referenced application, please amend the application as  
follows:

**IN THE SPECIFICATION:**